



ASTER
TECHNOLOGIES



Chiffres clés



28
YEARS

Private Limited
Company

55 Experts
WORLDWIDE

IPC CFX Standard

Headquarters in
FRANCE

Subsidiaries in
USA & UK

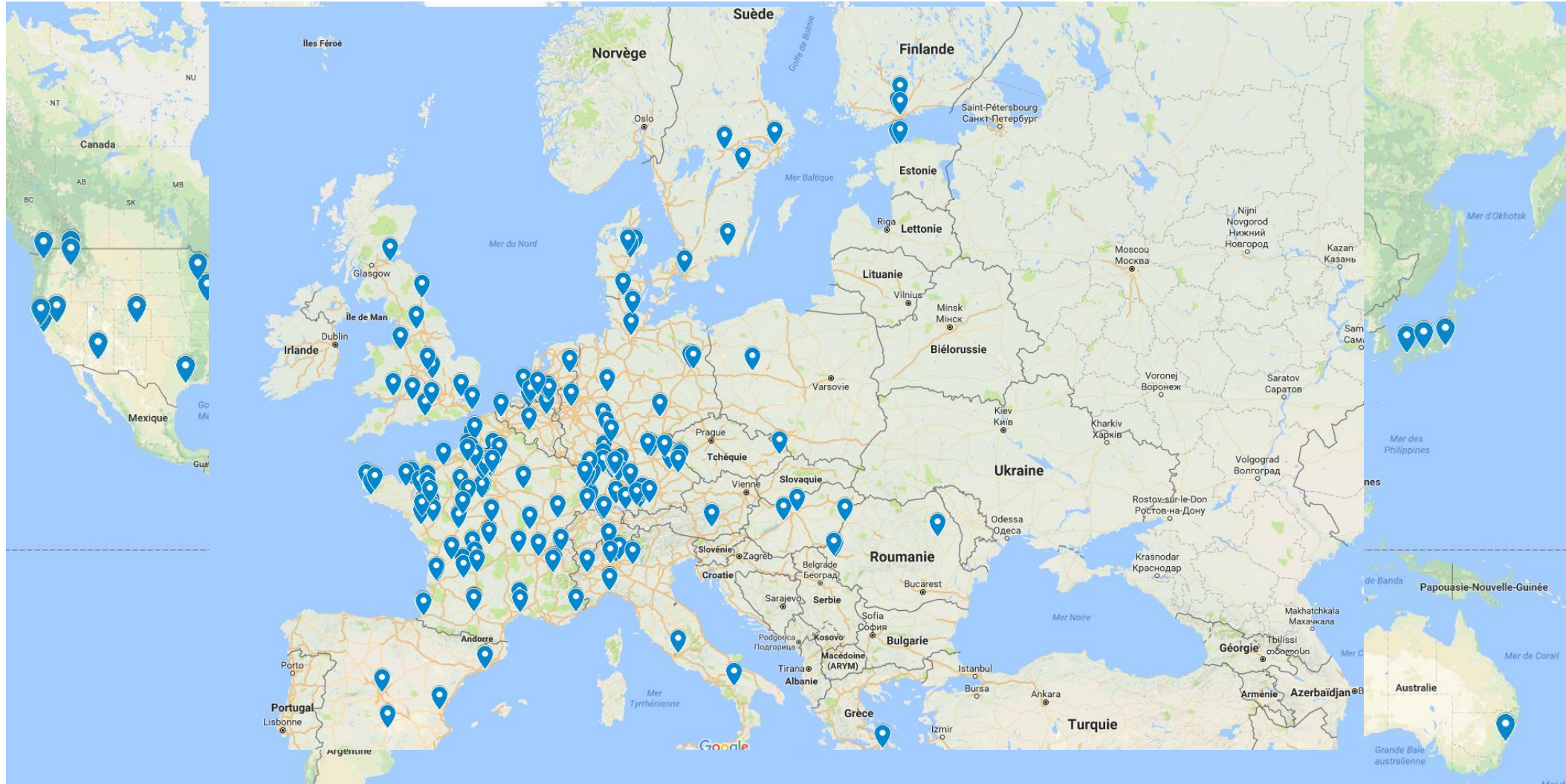
1200+
Installed Users

INNOVATION
R&D European
COLLABORATIVE
PROGRAMS

Distributed in over 25 COUNTRIES

CERTIFIED
Research Centre

Notre présence



55 Experts à travers le monde



Secteurs d'activités

Mission Critical



Aerospace & Military

Safety Critical



Automotive, Transportation, Medical

Board Complexity

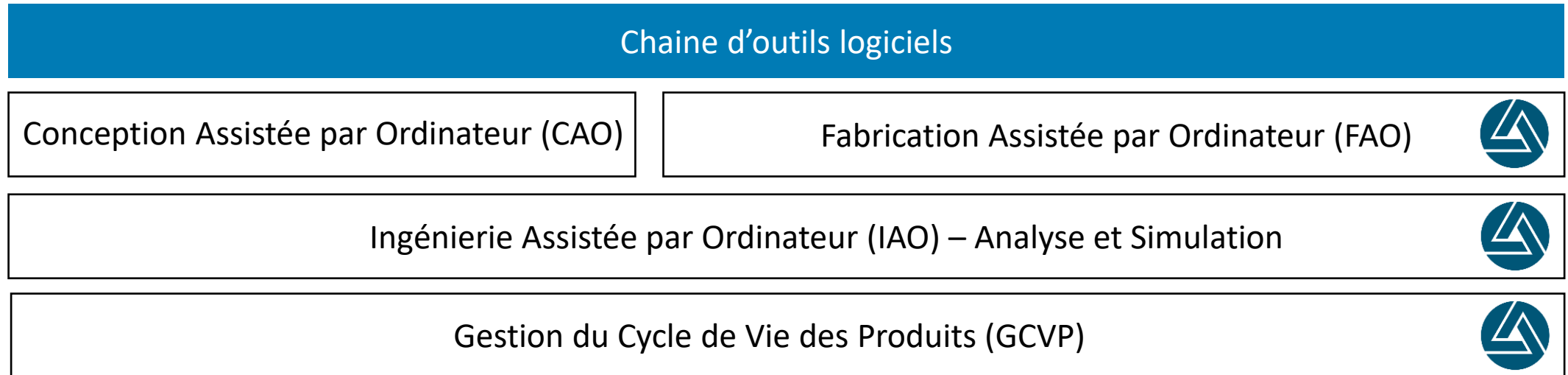
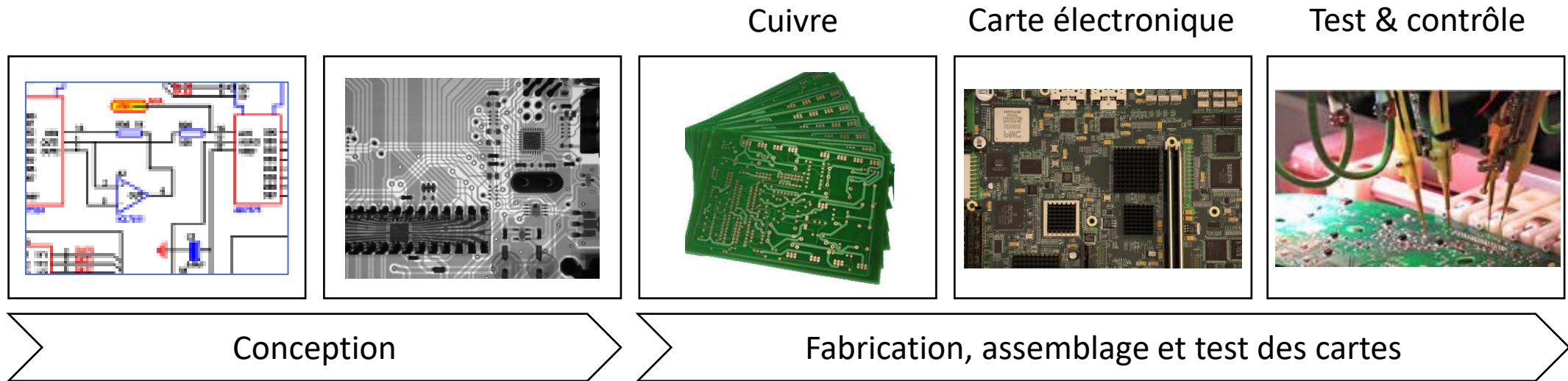


Consumer, Telecom, Industrial

Electronic Manufacturing Services



Processus de conception et de fabrication de cartes

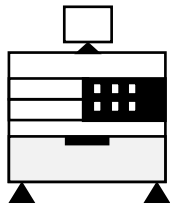




Support et services

Ecosystem ouvert

Prise en charge de plus de 60 types d'équipements d'Assemblage, AOI, AXI, ICT, FPT, BST & testeurs de Cable



Solutions de visualisation avancées

Layout

Schematic & Virtual Schematic

Fault-ticket Analyzer

3rd Party
Partenaires Software
Partenaires Hardware



Testabilité & Analyseur de couverture de Test & Simulation

Design for Test

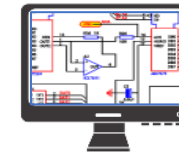
Predictive Test Coverage

Test Program Automation

Test Strategy Simulation

Real Coverage measurement

Test Report Automation



Traçabilité, diagnostic de pannes, analyses des données de fabrication

Licences logicielles: Permanente & Location



Nodelock

One Computer
One Seat

LAN

One Location
One Seat
or
Multiple Seats

NWAN

One Country
One Seat
or
Multiple Seats

CWAN

One Continent
One Seat
or
Multiple Seats

GWAN

Worldwide
One Seat
or
Multiple Seats

Le nombre de siege defini le nombre d'utilisateurs en simultanés par licence

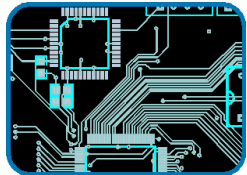


Nouvelle Generation de Visualisateur

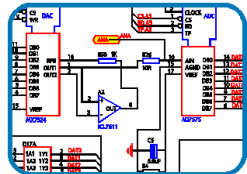
QuadView visualiser les cartes électroniques

- Visualisation simultanée et interactive
- Toutes les données dans un seul outil

Layout



Schematic



Bom

Ref	Part	QTY	UNIT	DESCRIPTION
MA1	CM5 ADB17AR	1	IC	CM5 ADB17AR
MA5	DSO BUF04G5	1	IC	DSO BUF04G5
R64	99182135_300	2	RES	99182135_300
C65	99164591_300	2	CAP	99164591_300
C76	10N/100V	1	CAP	10N/100V
C69	10N/100V	1	CAP	10N/100V



The screenshot shows the QuadView software interface with the following elements:

- Top Panel:** File menu, display options, and a toolbar.
- Left Panel:** Component list table with columns for Component, Pin, and other attributes.
- Main Area:** A detailed schematic diagram of a circuit with components like MA1 (CM5 ADB17AR), MA5 (DSO BUF04G5), R64, C65, C76, and C69. It shows power rails for +15V and -15V.
- Right Panel:** Pinout diagrams for components UN1AD81791PVS0 and UN1BUF0497P0UT0.
- Bottom Panel:** A 3D-like layout view of the PCB with a green box highlighting a specific component.

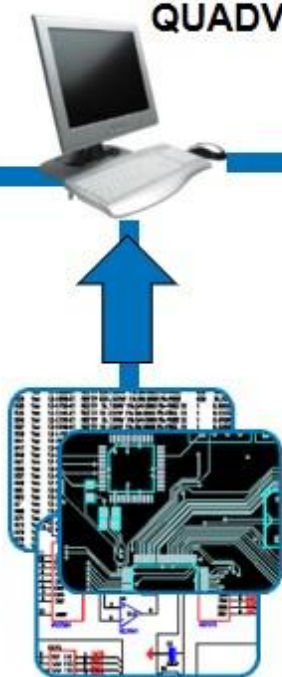
Station de réparation sans papiers

- Interface directe avec les moyens de test: GR228x, Z1800, Spectrum, HP3070, Takaya, SPEA, Cascon, ATEC...
- L'analyseur de ticket de faute est la solution sans papier pour faciliter les opérations de réparation des cartes complexes. Il s'adapte à votre propre environnement industriel et peut s'inclure dans votre cycle de réparation de cartes.

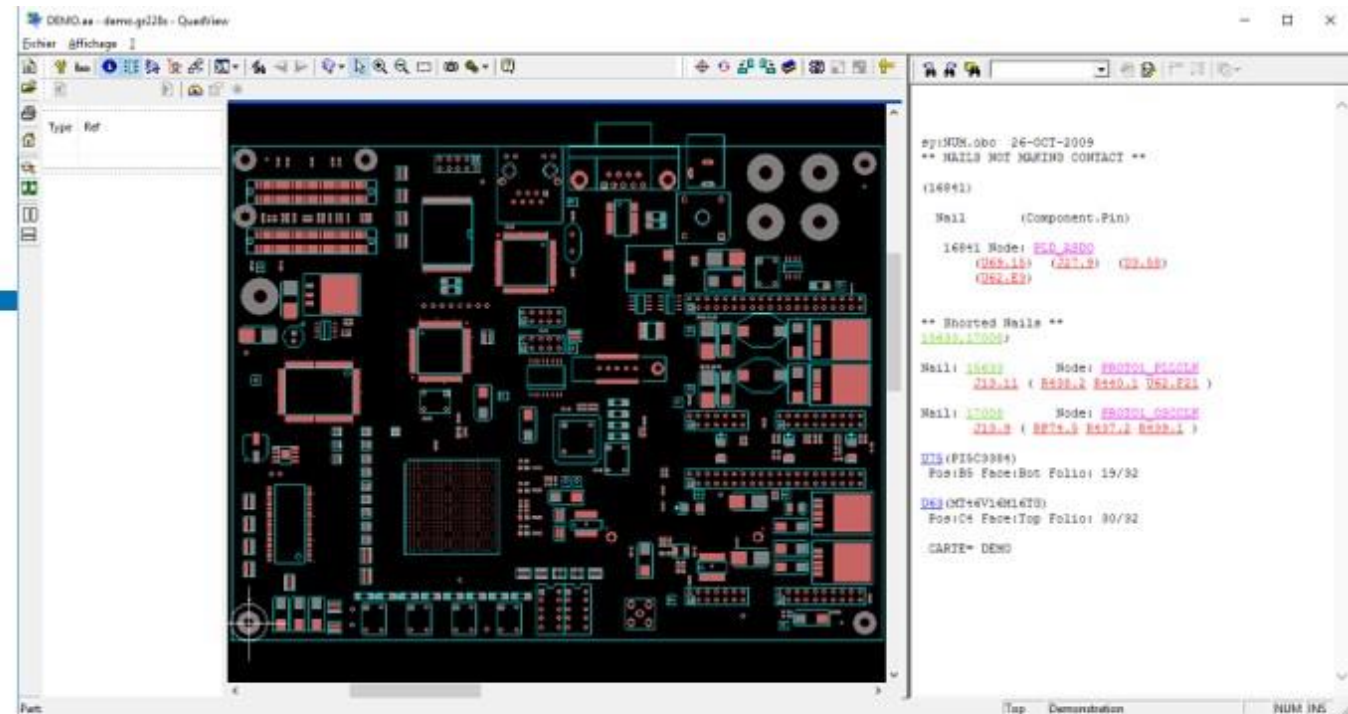
Test, inspection
& other machines



QUADVIEW

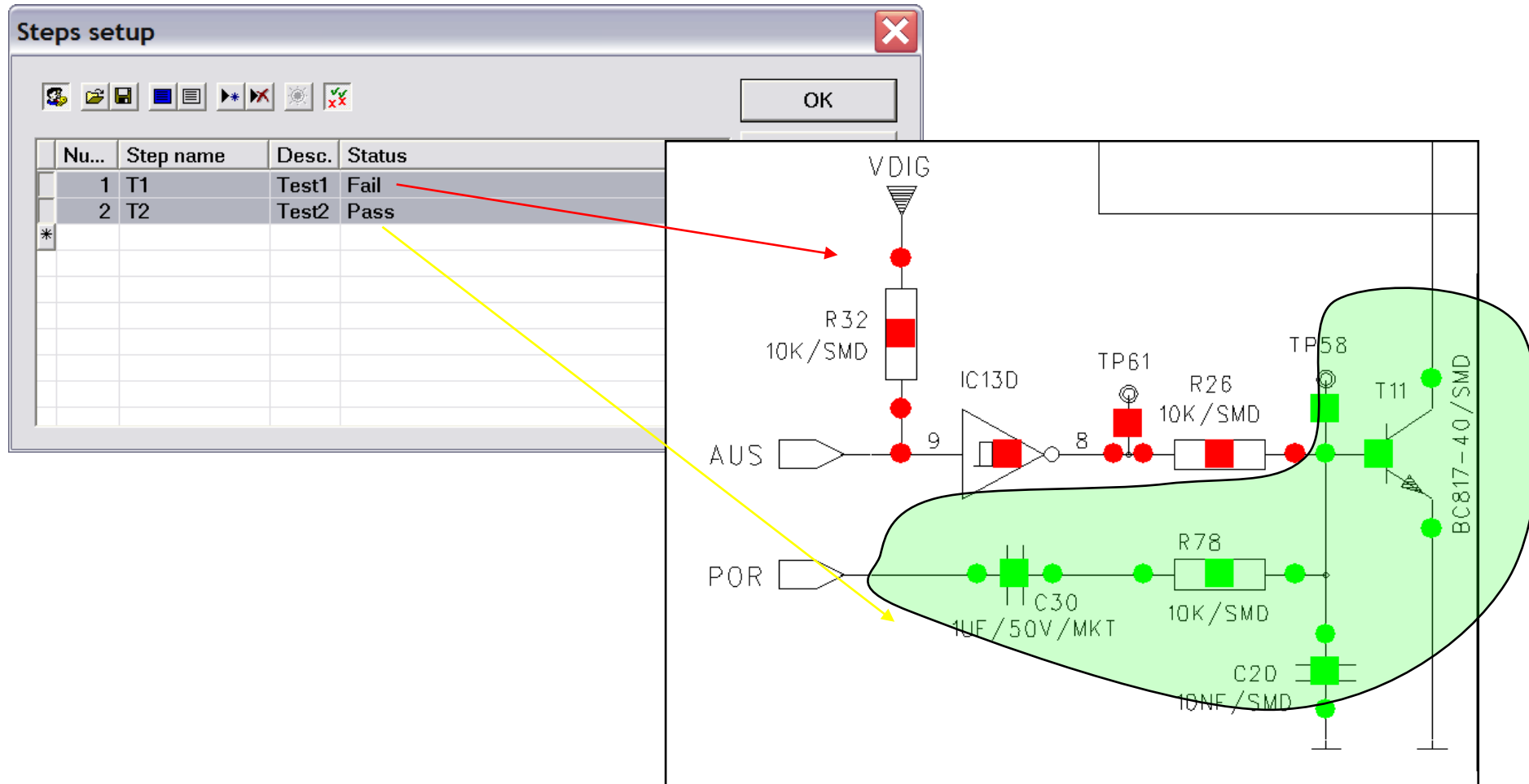


Design
data



« Sherlock » - Diagnostic

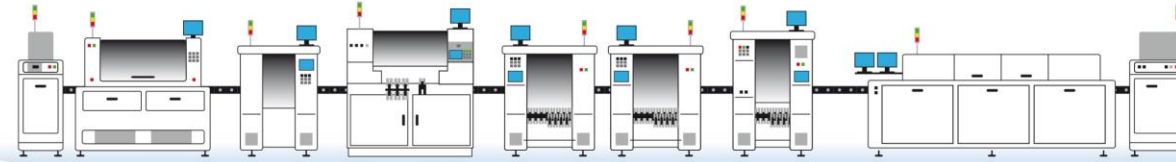
- Aide au diagnostic par l'analyse du recouvrement des tests fonctionnels



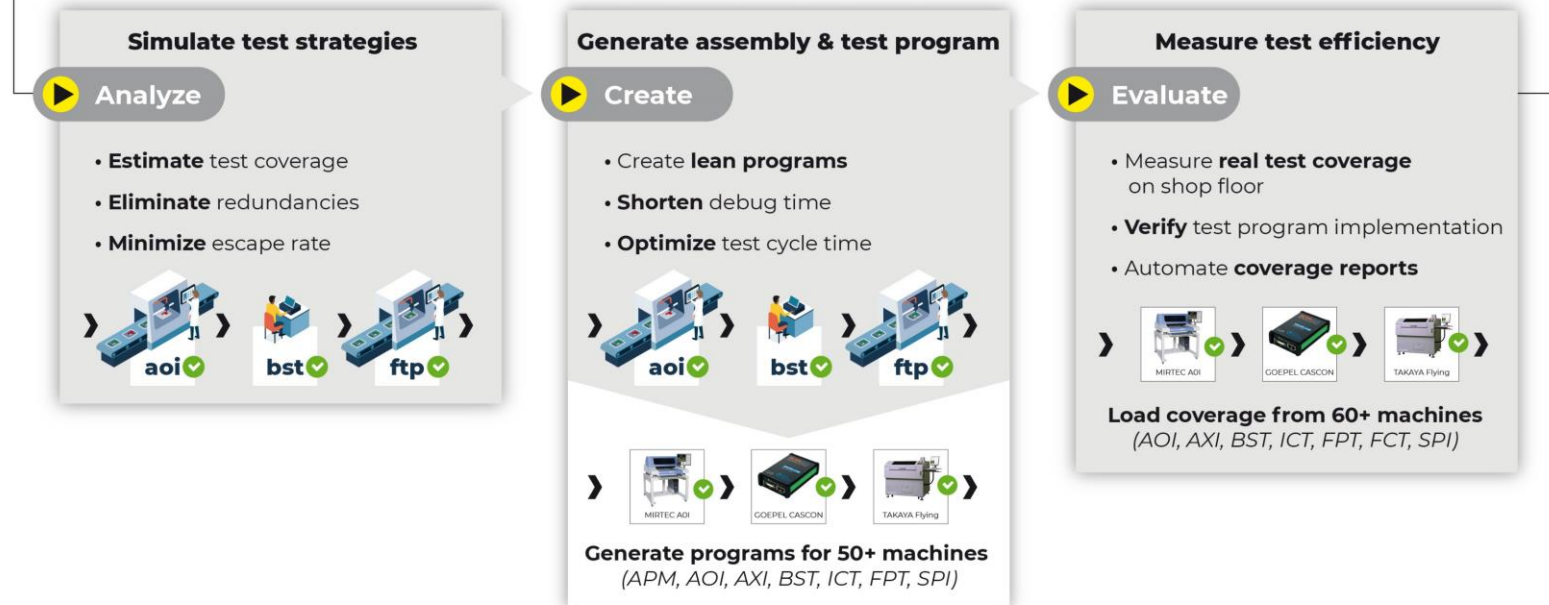


Design for Test and Test Coverage Analyzer

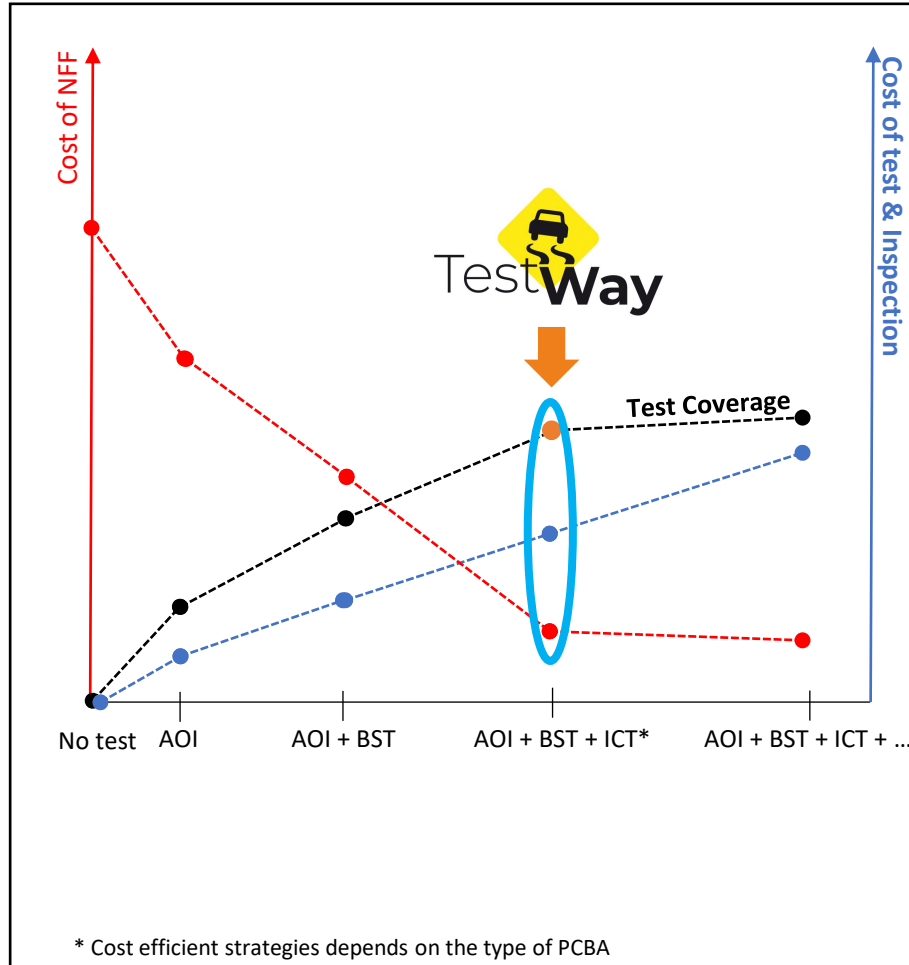
Software solutions for PCB Assembly & Test supporting industry 4.0



Digital twin powered
by TestWay™



Comment TestWay aide-t-il à mettre en œuvre une stratégie de test rentable?



TestWay permet de **simuler** différentes stratégies pour définir **la stratégie de test la plus rentable** en:

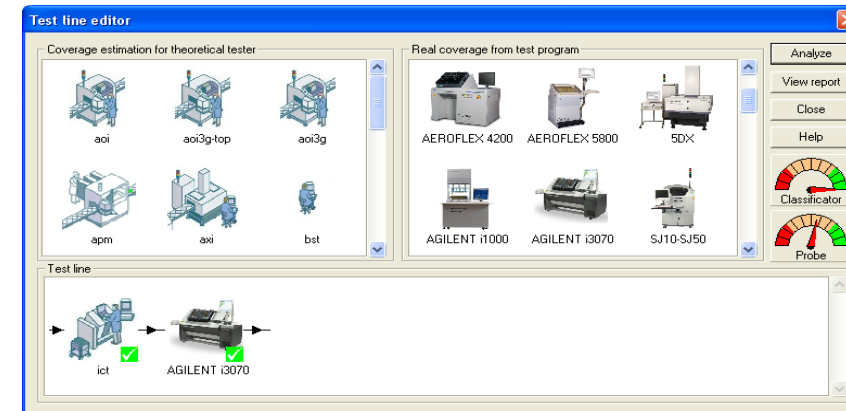
- Déterminant la **combinaison d'équipement de test** pour fournir **la meilleure estimation de couverture**
- **Éliminant les redondances** entre les testeurs pour **optimiser le temps de cycle**



TestWay permet de mesurer **la couverture de test réelle** pour chaque machine de test et d'inspection de la ligne de test



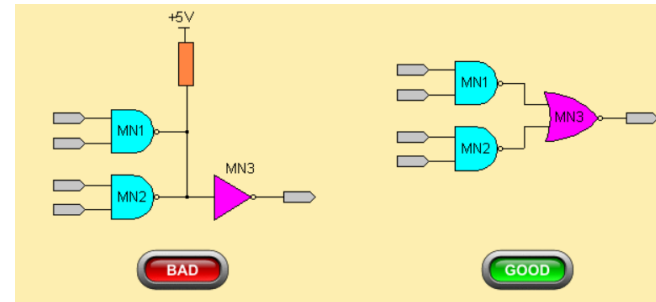
En comparant **«réel et estimé»**, les utilisateurs finaux peuvent vérifier que **la stratégie de test optimale** est effectivement mise en œuvre dans l'atelier.



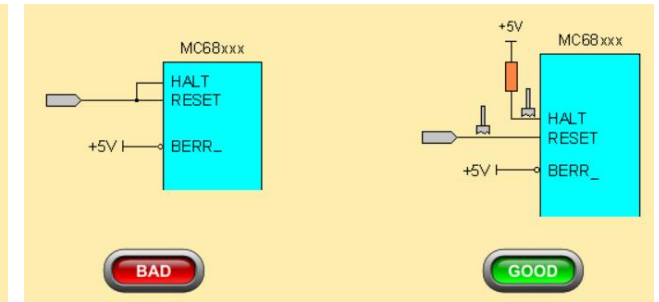
«si vous vous concentrez sur les coûts, vous perdez la qualité... si vous vous concentrez sur la qualité, vous réduisez les coûts »,TBP Electronics (EMS)

Vérification des règles de conception

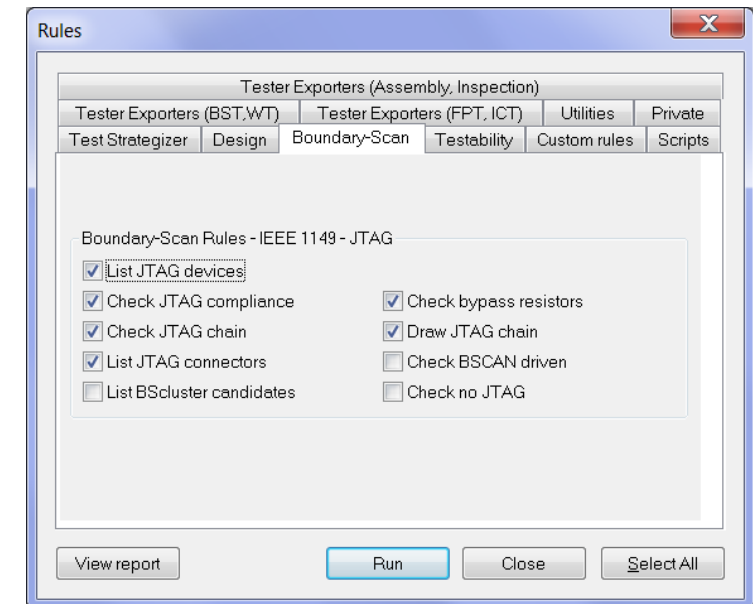
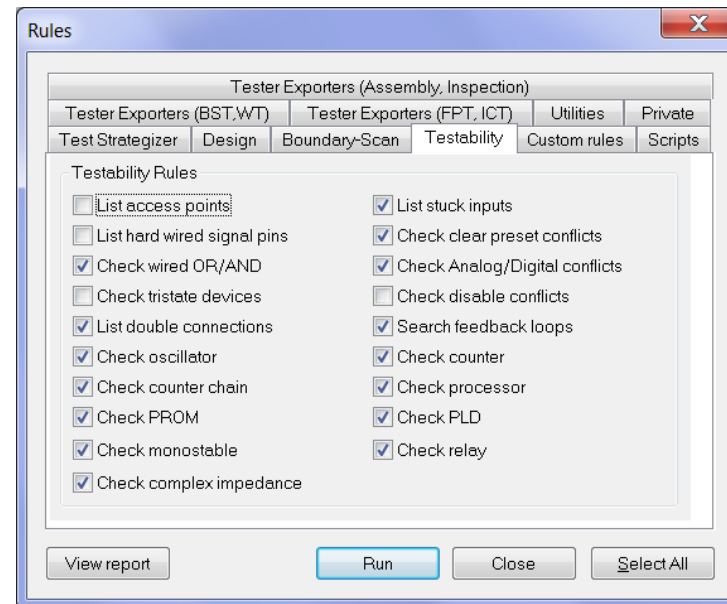
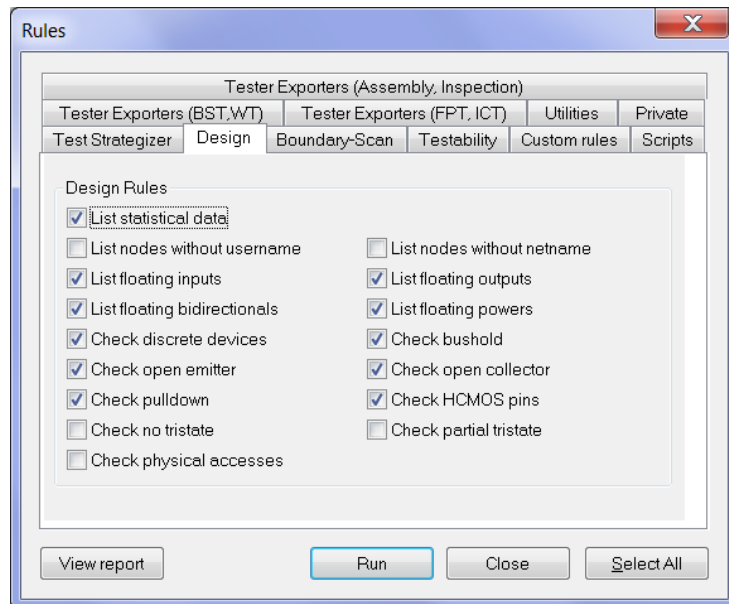
- TestWay Express analyse votre design dès les phases de schématique
 - ✓ Contrôle des règles de design
 - ✓ Contrôle des règles de testabilité
 - ✓ Contrôle des règles Boundary Scan
 - ✓ Possibilité d'ajouter ses propres règles



Check Wired OR/AND

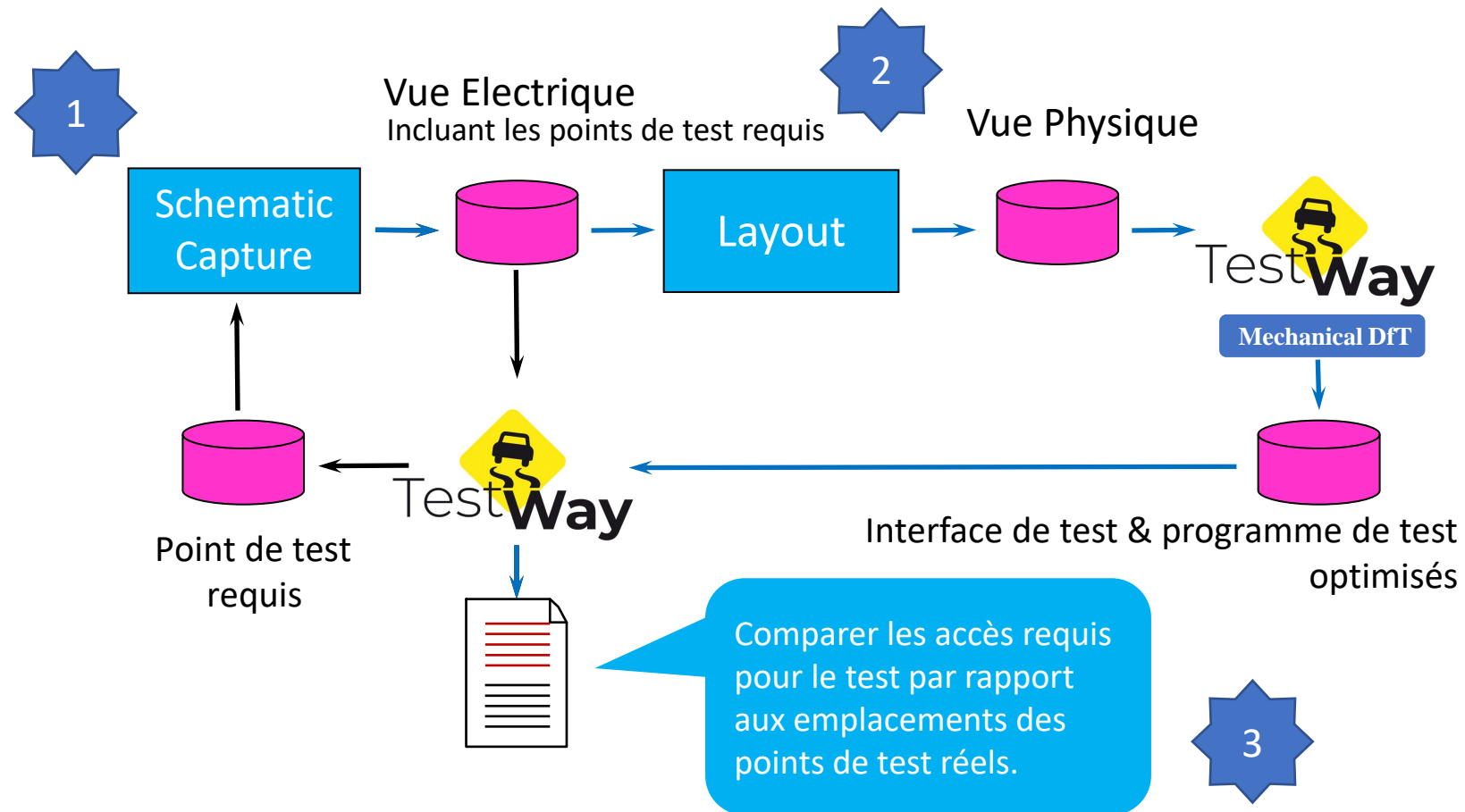


List double connections



Optimisation des points de test

- Identifier là où les points de test sont nécessaires



Placement des clous

- Les clous sont placés en respectant vos règles mécaniques et DFT

Probe Analyzer

Profile Priority rules Constraints Setup Probe Size Probe Quantity Display Rules

Unit: mm Shape definitions

Tester Type: Fixture Fixtureless

Minimum Feature Size: 0.3 SMD Pin Offset: 0.1

Package Outline Clearance: 0.127 Feature Clearance: 0.3175

Board Outline Clearance: 1.016 Tooling Hole Clearance: 2.54

Apply offset on THT pins: Minimum drill size for offset: 0.3

No offset on fitted parts: Use solder mask:

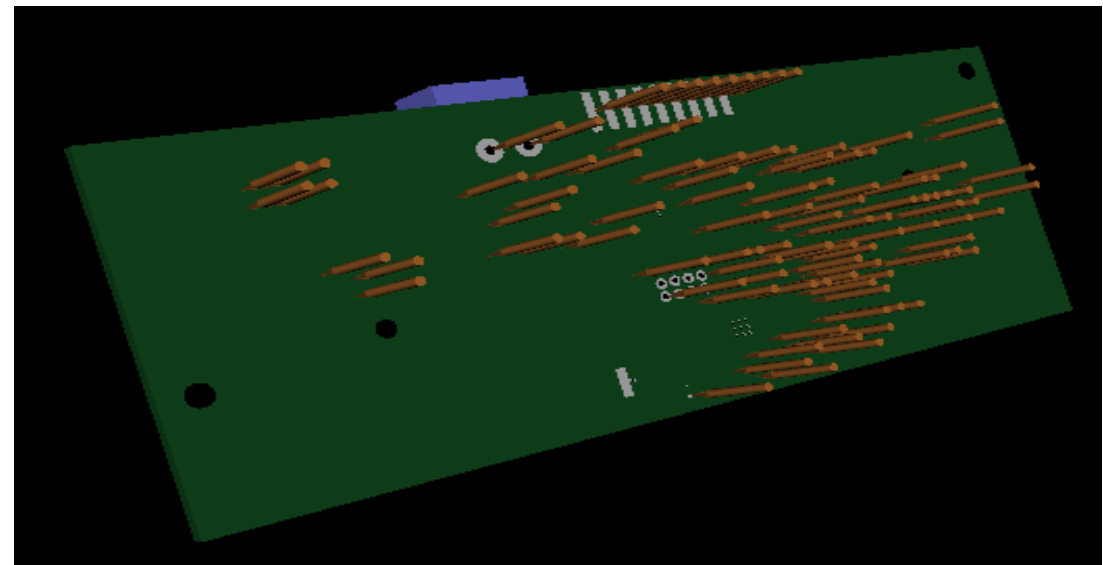
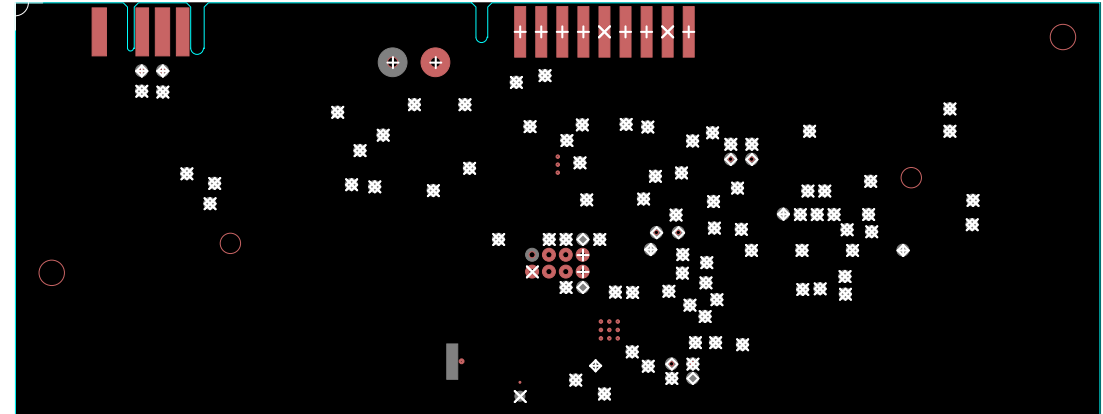
Ignore mount status: Solder Mask tolerance: 0

Ignore Mechanical: Keep alternate nails:

Include One-Pin Net: Include Multiple Pin Net:

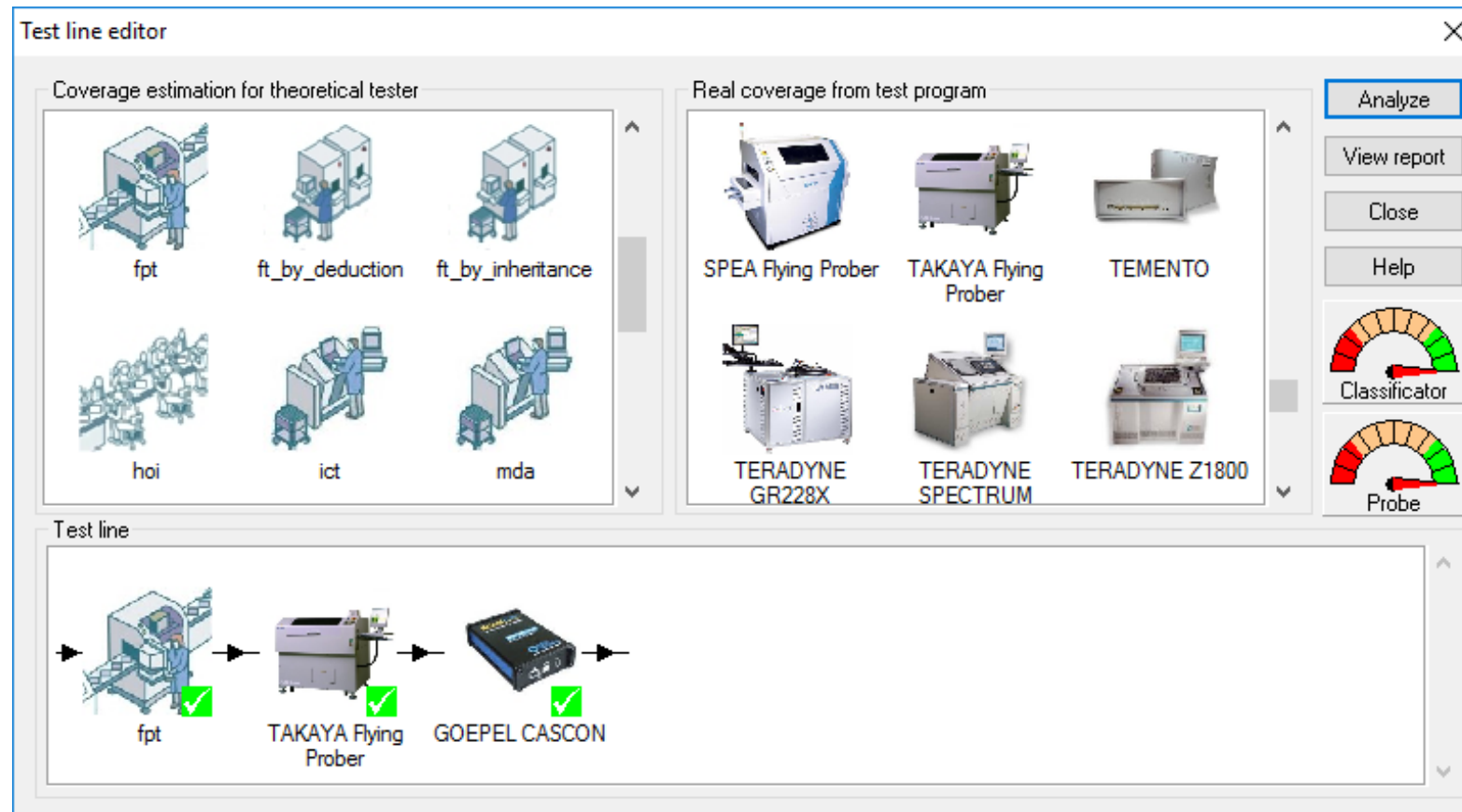
Nets	All Nets		Multiple Pin Nets		One-Pin Nets		NC Pin Nets	
	Total	Access.	Total	Access.	Total	Access.	Total	Access.
Top only	217	0 0%	115	0 0%	102	0 0%	0	
Bottom only	0	0	0	0	0	0	0	
Both	225	225 100%	199	199 100%	26	26 100%	0	
Total	442	225 50.9%	314	199 63.4%	128	26 20.3%	0	0

View report Analyze Close Help



Choix de la stratégie de test

- Définissez votre ligne de test avec de simple glisser-déposer
- Modèles de test théoriques ou réels



➤ Théorique:

- SPI
- AOI
- AXI
- FPT
- ICT
- BST

➤ Réel:

- Plus de 60 modèles réels
- Développements réguliers

Estimation de la couverture de test

- Paramétrer les testeurs pour des stratégies de test au plus proche de vos équipements
- Comparaison possible entre couverture prédictive et réelle

Tester settings

TestWay Express

Analyze and visualize the test coverage by simply importing the test program from a wide range of test & inspection equipments.

Name:

Tester:

Settings:

Parameter	Value
Access	Full
Dual side	<input type="checkbox"/>
TestPointSaver	<input type="checkbox"/>
Drive Thru	<input checked="" type="checkbox"/>
Powered Analog	<input checked="" type="checkbox"/>
Diode	Simple
OpenChecker	Yes
Camera	<input checked="" type="checkbox"/>
Absence Test	<input checked="" type="checkbox"/>
TestCoupon	<input type="checkbox"/>
Optimize IC	<input type="checkbox"/>
Optimize against AOI	<input type="checkbox"/>

Exports:

Buttons: OK, Cancel, Help, Setup origins

Tester settings

TestWay Express

Analyze and visualize the test coverage by simply importing the test program from a wide range of test & inspection equipments.

Name:

Tester:

Settings:

Parameter	Value
Access	Full
TestPointSaver	<input type="checkbox"/>
Unpowered Analog	<input checked="" type="checkbox"/>
Powered Analog	<input checked="" type="checkbox"/>
Digital	<input checked="" type="checkbox"/>
Connect Check	<input checked="" type="checkbox"/>
VectorLess Test	<input checked="" type="checkbox"/>
Polarity Check	<input type="checkbox"/>
NPM	<input type="checkbox"/>
Magic Test	<input type="checkbox"/>
Absence Test	<input checked="" type="checkbox"/>
InterconnectPlus	<input type="checkbox"/>

Exports:

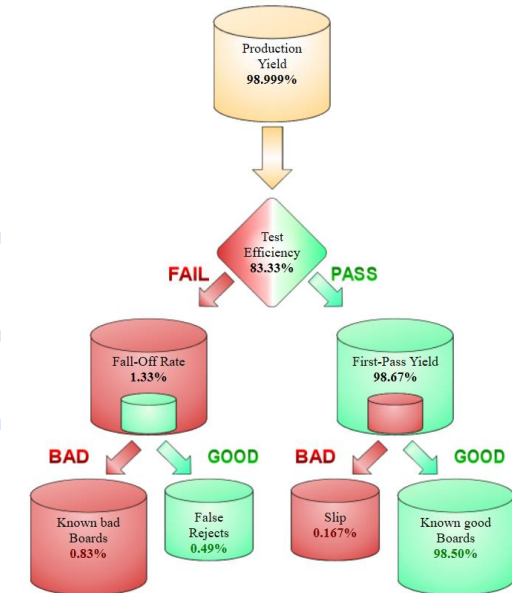
Buttons: OK, Cancel, Help, Setup origins

Tester	AOI	ICT
Test Coverage	34.88%	73.33%
Cumulative coverage	34.88%	83.33%
Escape rate	0.65%	0.17%




TEST REPORT FOR AOI/ICT

BOARD NAME / NUMBER	23730B-2	DATA PROCESSING REPORT	WKS:23730B_2A0M
COMPONENT	247	COMPONENT TESTED	99.23%
NET	117	NET ACCESS	71.79%
SHORT COVERAGE	74.11%	BOARD SCORE	83.33%

DEVICE TYPE	TOTAL NUMBER (PARTS OR PINS)	NUMBER OF WELL TESTED	NUMBER OF PARTIALLY TESTED	NUMBER OF NOT TESTED
INTEGRATED CIRCUIT	5 PARTS (165 PINS)	20.0% (1)	80.0% (4)	0.0% (0)
BATTERY	1 PARTS (13 PINS)	0.0% (0)	100.0% (1)	0.0% (0)
TRANSISTOR	6 PARTS	0.0% (0)	100.0% (6)	0.0% (0)
DIODE	8 PARTS	62.5% (5)	37.5% (3)	0.0% (0)
ZENER	1 PARTS	100.0% (1)	0.0% (0)	0.0% (0)
LED	2 PARTS	100.0% (2)	0.0% (0)	0.0% (0)
CAPACITOR	47 PARTS	36.2% (17)	63.8% (30)	0.0% (0)
RESISTOR	37 PARTS	100.0% (37)	0.0% (0)	0.0% (0)
INDUCTOR	11 PARTS	36.4% (4)	63.6% (7)	0.0% (0)
CRYSTAL	3 PARTS	33.3% (1)	66.7% (2)	0.0% (0)
SWITCH	1 PARTS	100.0% (1)	0.0% (0)	0.0% (0)
STRAP	5 PARTS (8 PINS)	100.0% (5)	0.0% (0)	0.0% (0)
CONNECTOR	2 PARTS (8 PINS)	50.0% (1)	0.0% (0)	50.0% (1)
NOT MOUNTED	118 PARTS			
TOTAL	129 PARTS (118 IGNORED)	58.1% (75)	41.1% (53)	0.8% (1)



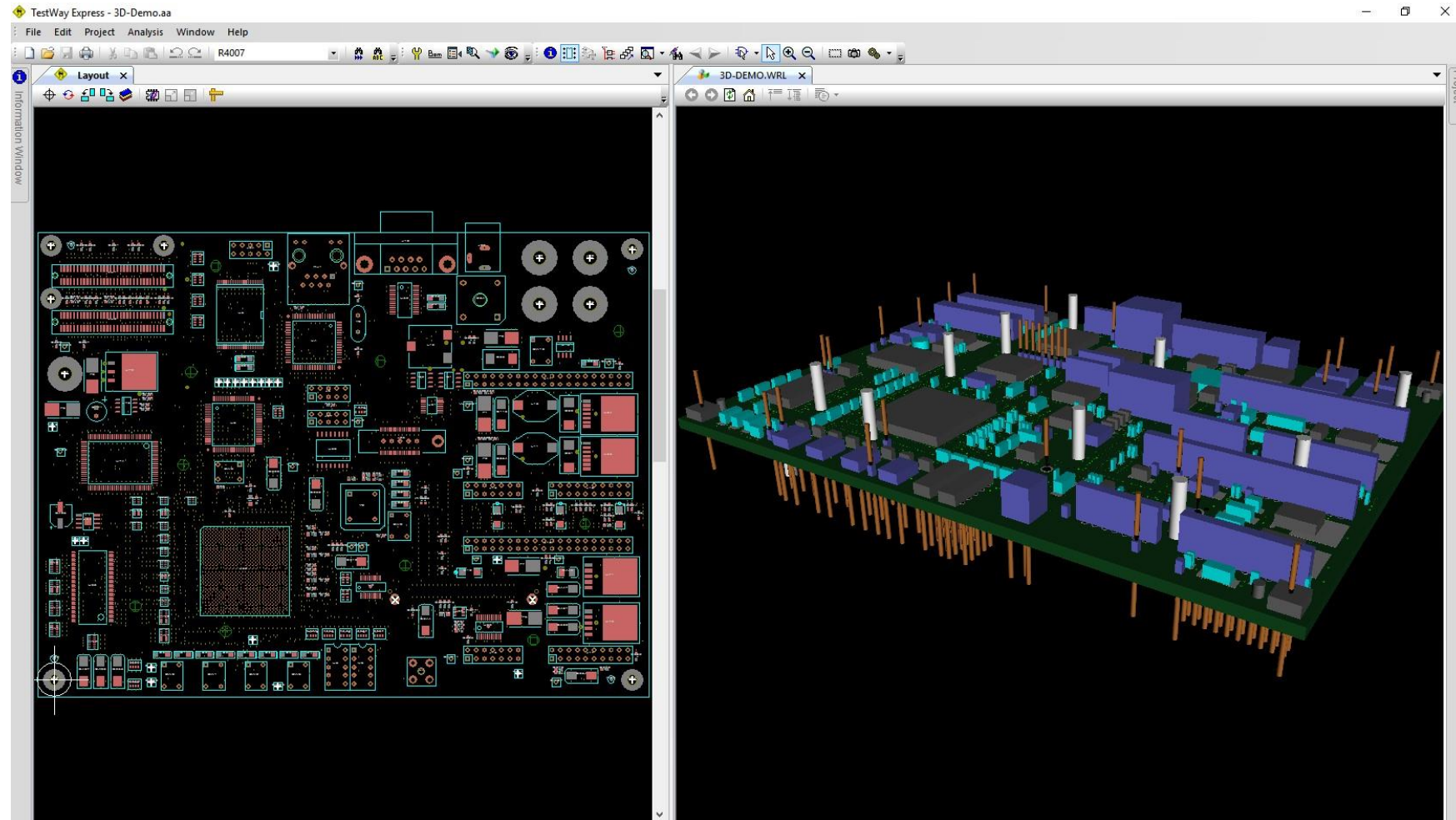
CAD2CAM convertisseurs générés par TestWay™

Assemblage	Inspection: AOI & AXI	Test: BST, ICT, FPT, Cables
		
<h2>Plus de 50 convertisseurs disponibles</h2>		
<p>Acculogic (BS), Aeroflex (IFR4200, IFR5800), ASSET, ASM (Siplace), Checksum, CableTest MPT, CIRRISSYSTEMS, CKT, CORELIS, CyberOptics, GEDIS, Europlacer, GOEPEL (CASCON, OPTICON), JTAG Tech, KeySight (SJ10, SJ50, i1000, i3070, x1149), MIRTEC, MYDATA, Panasonic, SAKI, (BF-Tristar, BF-Frontier, BFX2), SEICA (GRPilot, S20, VIVA), SIPLACE, SPEA (3030, 4040, 4050, 4060), TAKAYA (APT800, APT8000, APT9000, APT1400), TERADYNE (GR228x, TS124, Spectrum, Z1800), TRI (TR518, TR5001, TR7500, TR8001), VISCOM, VIT, ViTroX (V510, V810), WIZE.</p>		

Visualisateur 3D

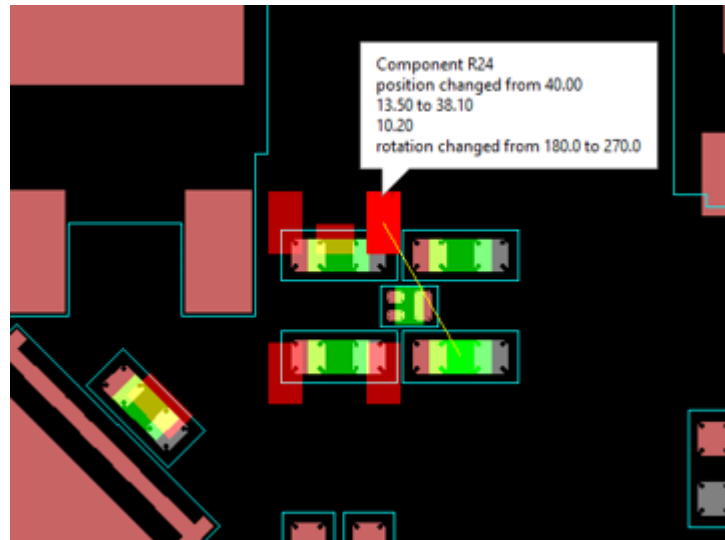
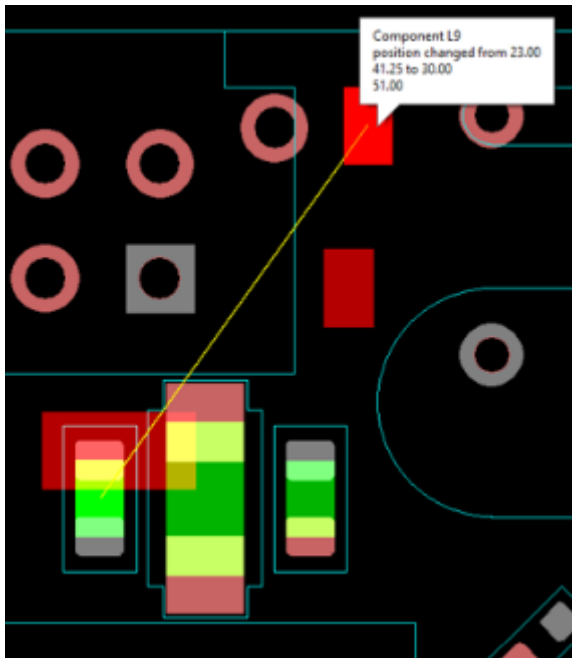
- Visualiser le placement de vos sondes de test dans une vue 3d de votre carte

- 2 formats générés :
 - ✓ VRML
 - ✓ X3D
- Rotation à 360° pour plus de détail
- Formats compatibles pour une impression 3D



Comparaison de version

- Visualiser les différences entre deux variantes de cartes
- Rapport HTML dynamique et visuel
 - ✓ Modification mécanique (position, rotation, Shape,...)
 - ✓ Modification électrique (Value, tol, point de test,...)



- Faciliter les modifications de programmes, d'interfaces,...)

Netlist file [test_jobA.aa](#) loaded from C:\Users\test\Desktop\Comparative data checker\Job A analysed on Fri Oct 11 16:02:04 2019.

Compare data between C:\Users\test\Desktop\Comparative data checker\Job A\test_jobA.aa and C:\Users\test\Desktop\Comparative data checker\Job B\JobB.aa.

▣ [Check part position \(22 differences\)](#)

▣ [Check part rotation \(10 differences\)](#)

The following parts have a different rotation.

Ref	BoardA	BoardB
D11	0.0	90.0
R22	180.0	270.0
R23	180.0	270.0
R24	180.0	270.0
R25	180.0	270.0
C22	180.0	0.0
C23	270.0	0.0
C51	90.0	270.0
D21	270.0	0.0
L2	90.0	0.0

There are 10 differences.

▣ [Check part shape \(2 differences\)](#)

▣ [Check part PartNumber \(not any difference\)](#)

▣ [Check part type \(not any difference\)](#)

▣ [Check added/removed parts \(1 difference\)](#)

▣ [Check part value \(not any difference\)](#)

▣ [Check part tol \(not any difference\)](#)

▣ [Check pin connectivity \(19 differences\)](#)

▣ [Check pin size \(36 differences\)](#)

▣ [Check added/removed physical test point \(not any difference\)](#)

▣ [Check test points \(not any difference\)](#)

▣ [Check nails \(119 differences\)](#)

twSystem : Visualiser un système électronique

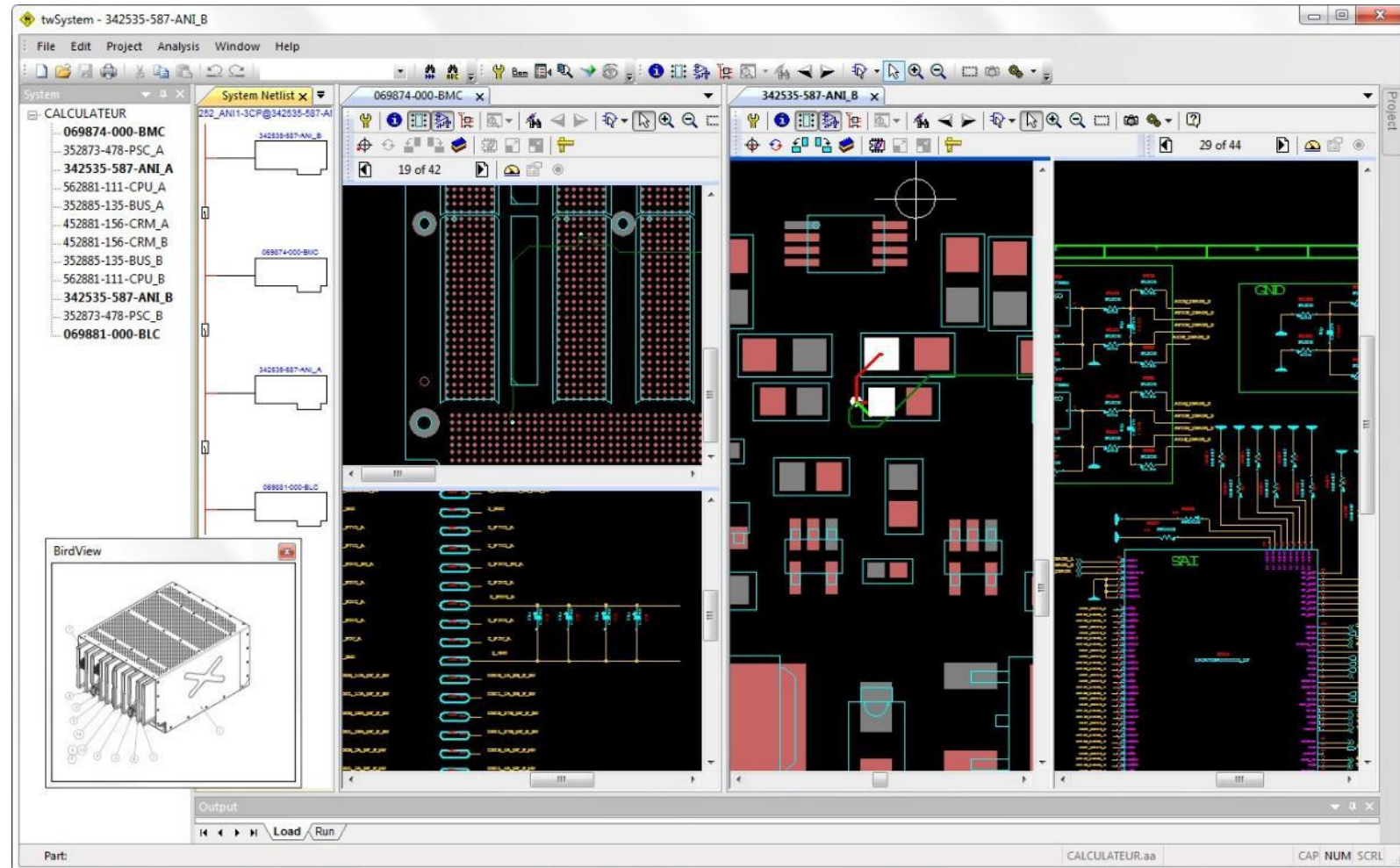
- Navigation interactive dans le système

- ✓ Cartes
- ✓ Fonds de panier
- ✓ Câbles

- Surbrillance des connexions sur chaque carte concernée

- twSystem peut être utilisé pour :

- ✓ Localiser les défauts
- ✓ Simplifier le dépannage
- ✓ Estimer la couverture de test
- ✓ Réaliser une couverture de test système





Traçabilité & Boucle de réparation
Composants, cartes & systèmes
Aide au diagnostic et à la réparation

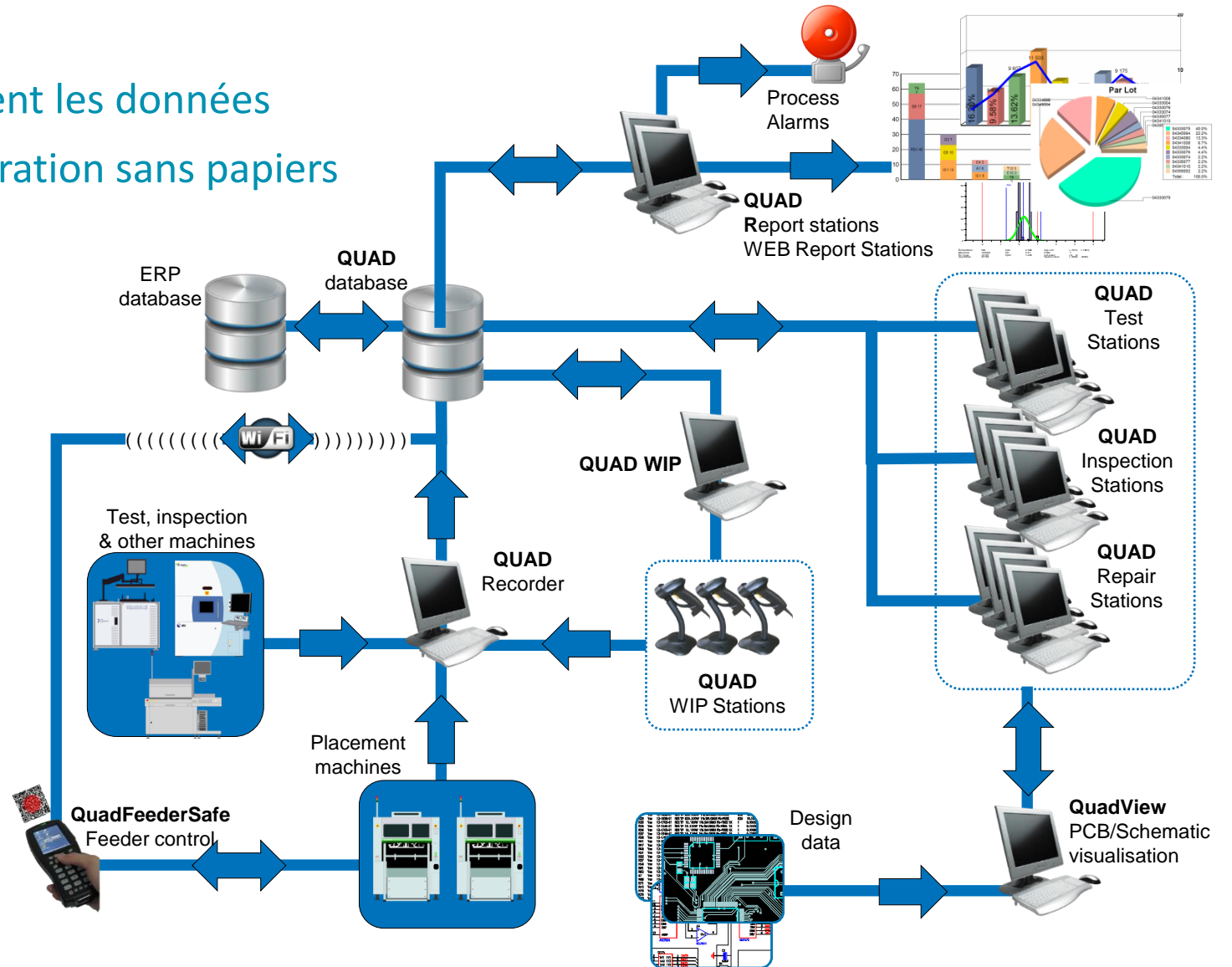


« Le pire des défauts est de les ignorer. »

Publius Syrus

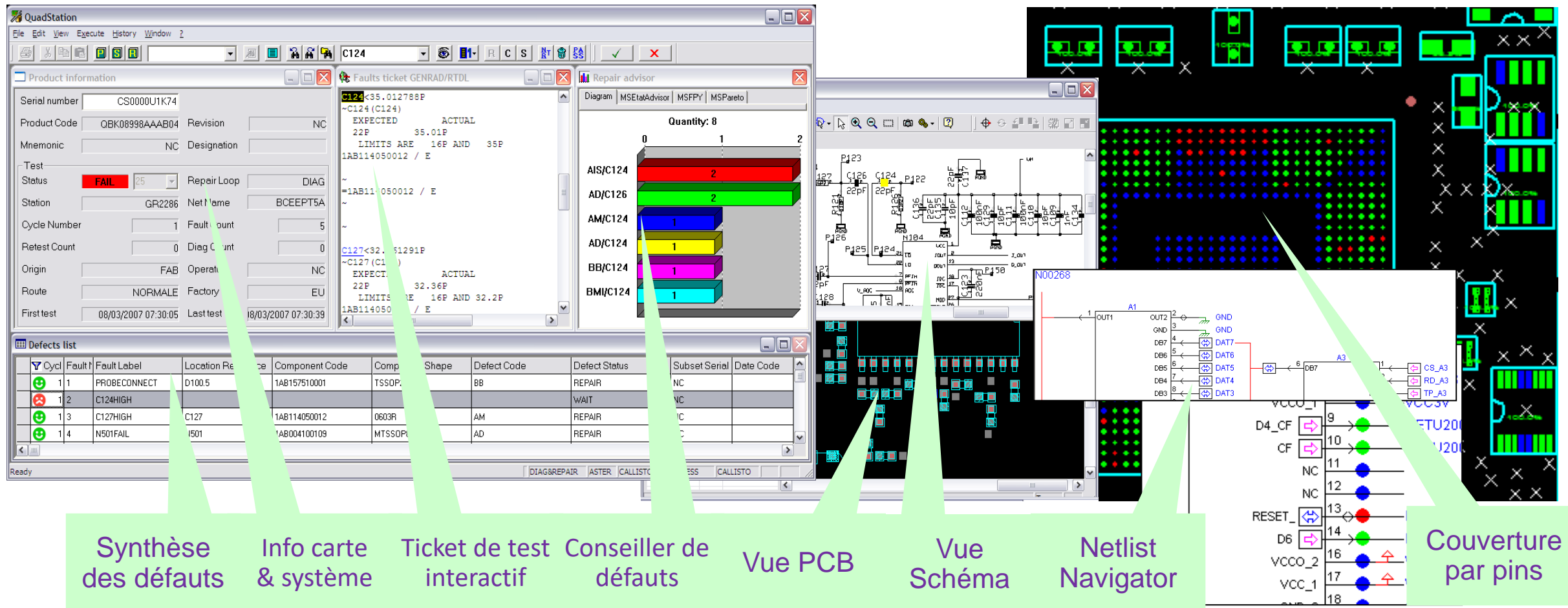
QUAD Vue d'ensemble

- Une base de donnée
- Un recorder pour collecter automatiquement les données
- La base est connectée aux stations de réparation sans papiers
- Peut s'interfacer avec un ERP
- Gestion matière :
 - ✓ Composants et stocks
 - ✓ Feeders
 - ✓ Plan de chargement
 - ✓ Traçabilité
 - ✓ MSL
- WIP gestion des encours
- Module d'analyse statistique et d'alertes
 - ✓ FPY
 - ✓ SPC
 - ✓ Cp, CpK
 - ✓ DPMO



Diagnostic & Réparations

- Interactivité totale entre toutes les vues
- L'ensemble des documents du produit à réparer sont disponibles à l'écran



The image displays the QuadStation software interface, which is used for diagnostic and repair of electronic components. The interface is divided into several panes and windows, each representing a different view of the product and its repair process.

Synthèse des défauts: A table listing defects with columns for Fault, Fault Label, Location Reference, Component Code, Component Shape, Defect Code, Defect Status, Subset Serial, and Date Code.

Symbol	Cycl	Fault	Fault Label	Location Reference	Component Code	Component Shape	Defect Code	Defect Status	Subset Serial	Date Code
🟢	1	1	PROBECCONNECT	D100.5	1AB157510001	TSSOP	BB	REPAIR	NC	
🔴	1	2	C124HIGH					WAIT	NC	
🟢	1	3	C127HIGH	C127	1AB114050012	0603R	AM	REPAIR	NC	
🟢	1	4	N501FAIL	N501	1AB004100109	MTSSOP	AD	REPAIR	NC	

Info carte & système: Product information window showing details like Serial number (CS0000U1K74), Product Code (QBK08998AAAB04), Revision (NC), Mnemonic (NC), Designation, Station (GR2286), Net Name (BCEEPT5A), Cycle Number (1), Fault Count (5), Retest Count (0), Diag Count (0), Origin (FAB), Operate (NC), Route (NORMALE), Factory (EU), First test (08/03/2007 07:30:05), and Last test (08/03/2007 07:30:39).

Ticket de test interactif: Faults ticket window showing test results for components like C124 and C127, including expected and actual values and limits.

Conseiller de défauts: Repair advisor window showing a bar chart of quantities for various components (AIS/C124, AD/C126, AM/C124, AD/C124, BB/C124, BM/C124).

Vue PCB: PCB view window showing the physical layout of the board with components and their locations.

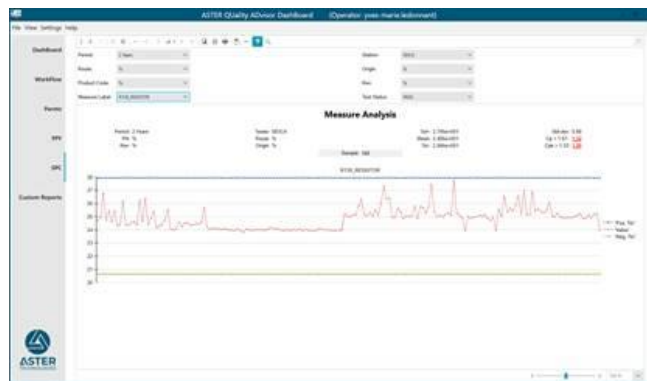
Vue Schéma: Schematic view window showing the electrical circuit diagram of the board.

Netlist Navigator: Netlist Navigator window showing a hierarchical view of the netlist, including components like N00268 and their connections.

Couverture par pins: Coverage by pins window showing a grid of pins and their coverage status, with various pins labeled like D4_CF, CF, NC, RESET, D6, VCCO_2, VCCO_1, VCCO_3V.

Suivi Qualité

- Génération de rapports s'appuyant sur Crystal Report (SAP) et les bibliothèques Telerik
 - ✓ Rapports texte et graphique hautement programmable
 - ✓ Diffusion par le WEB
 - ✓ Génération automatisé d'alarmes



HISTORIQUE PRODUIT

043450681DE3

N° de série: 043450681DE3

Date: vendredi, 15 octobre 2004

Code produit: 13777550114

Carte: C CONTROLE INVER

Révision produit: 10

Lot: 04345068

Date	Testeur	Cycle	Diagnostic & Réparation	Défaut	Nb Fau	Statut
08-09-04	GENRAD 2201574	1	Nombre de RESTART après un: PASS: 0 DIAG: 0, FAIL: 0 ABORT: 0 DIAGNOSTIC: Op: essai Origine: FAB Diag Date : 03/09/2004 07:08:51 - Route: NORMALE Op: 04403 03/09/04 07:09:06 03/09/04 07:09:11 Tps test: 0 S CEC C2 Pin 1	1	1	FAIL
09 h 40			REPARATION: Op: essai Repair Date : 03/09/2004 07:08:51 - 03/09/2004 07:11:58 Tps de rép.: 187 S			END
08-09-04	GENRAD 2201574	2	Nombre de RESTART après un: PASS: 0 DIAG: 0, FAIL: 1 ABORT: 0 DIAGNOSTIC: Op: Tps de diag.: 0 S	1		PASS
09 h 40			REPARATION: Op: Tps de rép.: 0 S			END



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Responsable des ventes

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